

Amendments to the Specification:

Please replace the paragraph at page 7, lines 14-30 with the following rewritten paragraph:

Operations of the clock generation circuit **100** in accordance with embodiments of the present invention will now be further described with reference to **FIG. 1**. It will be understood that the temperature sensor characteristics of the temperature sensor **210** may change due to variations in the manufacturing process used to produce the clock generation circuit **100**. As a result, errors in indicated operating temperature range may be encountered. For example, the temperature of ~~an~~ ~~na~~ integrated circuit (semiconductor) memory device including the clock generation circuit **100** may, as initially fabricated, be erroneously indicated as operating at a range about 80°C when the real operating temperature is in a range about 100°C. This condition may be addressed in the test mode by selecting the value of the temperature coding signal *TEMPCODES* to cut ones of the plurality of fuses of the calibration circuit of the temperature sensor circuit **110** so that the temperature sensor **110** more accurately indicates the operational temperature. It is to be understood that the fuses may be part of the temperature sensor **210** so that the output *SENSOUT* is calibrated by the calibration circuit of the temperature sensor circuit **110** as illustrated in the embodiments of **FIG. 2** or that the calibration circuit be separate from the temperature sensor **210** and calibrate the output signal *TEMPS* relative to the output *SENSOUT*.